Analog Devices Welcomes Hittite Microwave Corporation

NO CONTENT ON THE ATTACHED DOCUMENT HAS CHANGED
LAT Flow for Space Qualified MMIC Chip (Die)

1. Configure LAT Samples
   • Configured from Process Flow for Space Qualified MMIC Die, Item 12.
   • Sample selection per MIL-PRF-38534, Appendix C, Paragraph C.3.3.4.1.

2. Assemble Fixtured Samples
   • Die Mount in RF Test Fixture
   • Wire Bond
   • Serialize

3. 100% MMIC Visual Inspection, per MIL-STD-883, Method 2017, Class H

4. Temperature Cycle
   • MIL-STD-883, Method 1010, Condition C, -65° C to +150° C, 10 cycles

5. Pre-Burn-In RF Test
   • Per Customer Specification
   • Read and Record Data

6. Burn-In
   • MIL-STD-883, Method 1015, Class S, DC Biased

7. Post-Burn-In RF Test
   • Per Customer Specification
   • Read and Record Data

8. Post Burn-In Delta Calculation
   • Per Customer Specification

9. High Temperature Operating Life (HTOL) Test
   • MIL-STD-883, Method 1005, Class S, DC Biased

10. Post-HTOL RF Test
    • Per Customer Specification

11. Post-HTOL Test Delta Calculation
    • Per Customer Specification
    • Read and Record Data

12. Final LAT Report
    • Summary Data
    • Detailed Data
    • Results